9-BIT BUS-INTERFACE REGISTER WITH 3-STATE OUTPUTS

SCCS069A - OCTOBER 2001 - REVISED NOVEMBER 2001

- Function, Pinout, and Drive Compatible
 With FCT, F Logic, and AM29823
- Reduced V_{OH} (Typically = 3.3 V) Version of Equivalent FCT Functions
- Edge-Rate Control Circuitry for Significantly Improved Noise Characteristics
- I_{off} Supports Partial-Power-Down Mode Operation
- Matched Rise and Fall Times
- Fully Compatible With TTL Input and Output Logic Levels
- ESD Protection Exceeds JESD 22
 - 2000-V Human-Body Model (A114-A)
 - 200-V Machine Model (A115-A)
 - 1000-V Charged-Device Model (C101)
- 64-mA Output Sink Current
 32-mA Output Source Current
- High-Speed Parallel Register With Positive-Edge-Triggered D-Type Flip-Flops
- Buffered Common Clock-Enable (EN) and Asynchronous-Clear (CLR) Inputs
- 3-State Outputs

(TOP VIEW) 24 🛮 V_{CC} <u>oe</u> l $D_0 \square 2$ 23 Y_0 $D_1 \square 3$ 22 X1 $D_2 \square 4$ 21 Y₂ $D_3 \square 5$ 20 Y₃ $D_4 \begin{bmatrix} 1 \\ 6 \end{bmatrix}$ 19 Y₄ D₅ [] 7 18 Y₅ $D_6 \square 8$ 17 X Y₆ $D_7 \begin{bmatrix} 1 \\ 9 \end{bmatrix}$ 16 Y₇ 15 🛮 Y₈ D₈ [] 10 14 EN CLR **∏** 11 GND 12 13 CP

P. Q. OR SO PACKAGE

description

This bus-interface register is designed to eliminate the extra packages required to buffer existing registers and provide extra data width for wider address/data paths or buses carrying parity. The CY74FCT823T is a 9-bit-wide buffered register with clock-enable (EN) and clear (CLR) inputs that are ideal for parity bus interfacing in high-performance microprogrammed systems. It is ideal for use as an output port requiring high I_{OL}/I_{OH}.

This device is designed for high-capacitance load drive capability, while providing low-capacitance bus loading at both inputs and outputs. Outputs are designed for low-capacitance bus loading in the high-impedance state.

This device is fully specified for partial-power-down applications using I_{off}. The I_{off} circuitry disables the outputs, preventing damaging current backflow through the device when it is powered down.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.



ORDERING INFORMATION

TA	PACI	KAGEŤ	SPEED (ns)	ORDERABLE PART NUMBER	TOP-SIDE MARKING
	QSOP - Q	Tape and reel	6	CY74FCT823CTQCT	FCT823C
	SOIC - SO	Tube	6	CY74FCT823CTSOC	FCT823C
	3010 = 30	Tape and reel	6	CY74FCT823CTSOCT	FC1023C
-40°C to 85°C	DIP – P	Tube	7.5	CY74FCT823BTPC	CY74FCT823BTPC
-40 C to 83 C	DIP – P	Tube	10	CY74FCT823ATPC	CY74FCT823ATPC
	QSOP - Q	Tape and reel	10	CY74FCT823ATQCT	FCT823A
	SOIC - SO	Tube	10	CY74FCT823ATSOC	FCT823A
	3010 - 30	Tape and reel	10	CY74FCT823ATSOCT	FUIOZSA

[†] Package drawings, standard packing quantities, thermal data, symbolization, and PCB design guidelines are available at www.ti.com/sc/package.

PIN DESCRIPTION

NAME	1/0	DESCRIPTION
D	I	D flip-flop data inputs
CLR	I	When CLR is low and OE is low, Q outputs are low. When CLR is high, data can be entered into the register.
СР	0	Clock pulse for the register. Enters data into the register on the low-to-high clock transition.
Υ	0	Register 3-state outputs
EN	I	Clock enable. When \overline{EN} is low, data on the D input is transferred to the Q output on the low-to-high clock transition. When \overline{EN} is high, the Q outputs do not change state, regardless of the data or clock input transitions.
ŌĒ	I	Output control. When \overline{OE} is high, the Youtputs are in the high-impedance state. When \overline{OE} is low, true register data is present at the Youtputs.

FUNCTION TABLE

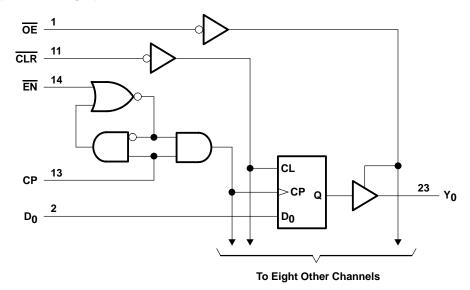
	1	INPUTS				RNAL PUTS	FUNCTION
OE	CLR	EN	D	СР	Q	Υ	
Н	Н	L	L	↑	L	Z	Z
Н	Н	L	Н	\uparrow	Н	Z	۷
Н	L	Χ	Χ	Х	L	Z	Clear
L	L	Χ	Χ	Х	L	L	Clear
Н	Н	Н	Х	Х	NC	Z	Hold
L	Н	Н	Χ	Х	NC	NC	Hold
Н	Н	L	L	1	L	Z	
Н	Н	L	Н	\uparrow	Н	Z	Load
L	Н	L	L	\uparrow	L	L	Load
L	Н	L	Н	1	Н	Н	

H = High logic level, L = Low logic level, X = Don't care, NC = No change,



^{↑ =} Low-to-high transition, Z = High-impedance state

logic diagram (positive logic)



absolute maximum rating over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range to ground potential	
DC output voltage range	
DC output current (maximum sink current/pin)	120 mA
Package thermal impedance, θ _{JA} (see Note 1): P package	67°C/W
(see Note 2): Q package	61°C/W
(see Note 2): SO package	46°C/W
Ambient temperature range with power applied, T _A	-65°C to 135°C
Storage temperature range, T _{stg}	-65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The package thermal impedance is calculated in accordance with JESD 51-3.
 - 2. The package thermal impedance is calculated in accordance with JESD 51-7.

recommended operating conditions (see Note 3)

		MIN	NOM	MAX	UNIT
Vcc	Supply voltage	4.75	5	5.25	V
VIH	High-level input voltage	2			V
VIL	Low-level input voltage			0.8	V
ІОН	High-level output current			-32	mA
lOL	Low-level output current			64	mA
TA	Operating free-air temperature	-40		85	°C

NOTE 3: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation.



SCCS069A - OCTOBER 2001 - REVISED NOVEMBER 2001

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITION	S	MIN	TYP [†]	MAX	UNIT
VIK	$V_{CC} = 4.75 \text{ V},$	I _{IN} = -18 mA			-0.7	-1.2	V
\/a	\/a a 4.75.\/	I _{OH} = -32 mA		2			V
VOH	V _{CC} = 4.75 V	I _{OH} = -15 mA	2.4	3.3		V	
VOL	V _{CC} = 4.75 V,	I _{OL} = 64 mA			0.3	0.55	V
V _{hys}	All inputs				0.2		V
Ι _Ι	$V_{CC} = 5.25 \text{ V},$	$V_{IN} = V_{CC}$				5	μΑ
lін	V _{CC} = 5.25 V,	$V_{IN} = 2.7 \text{ V}$				±1	μΑ
Ι _{ΙL}	V _{CC} = 5.25 V,	$V_{IN} = 0.5 V$				±1	μΑ
lozh	V _{CC} = 5.25 V,	V _{OUT} = 2.7 V				10	μΑ
lozL	V _{CC} = 5.25 V,	V _{OUT} = 0.5 V				-10	μΑ
los [‡]	$V_{CC} = 5.25 \text{ V},$	V _{OUT} = 0 V		-60	-120	-225	mA
l _{off}	$V_{CC} = 0 V$,	V _{OUT} = 4.5 V				±1	μΑ
Icc	$V_{CC} = 5.25 \text{ V},$	$V_{IN} \le 0.2 V$	$V_{IN} \ge V_{CC} - 0.2 \text{ V}$		0.1	0.2	mA
ΔlCC	V _{CC} = 5.25 V, V _{IN} =	3.4 V\$, f ₁ = 0, Outputs or	oen		0.5	2	mA
ICCD¶	$\frac{V_{CC}}{OE} = \frac{5.25}{EN} $	it switching at 50% duty c $1 \le 0.2 \text{ V or V}_{IN} \ge \text{V}_{CC} - 0$	cycle, Outputs open, 0.2 V		0.06	0.12	mA/ MHz
		One bit switching at f ₁ = 5 MHz	$V_{IN} \le 0.2 \text{ V or}$ $V_{IN} \ge V_{CC} - 0.2 \text{ V}$		0.7	1.4	
#	$V_{CC} = 5.25 \text{ V},$	at 50% duty cycle	V _{IN} = 3.4 V or GND		1.2	3.4	A
ıC.,	$I_{C}^{\#}$ Outputs open, $\overline{OE} = \overline{EN} = \overline{GND}$	Eight bits switching at f ₁ = 2.5 MHz	$V_{IN} \le 0.2 \text{ V or}$ $V_{IN} \ge V_{CC} - 0.2 \text{ V}$		1.6	3.2	mA
		at 50% duty cycle	V _{IN} = 3.4 V or GND		3.9	12.2	
Ci					5	10	pF
Co					9	12	pF

[†] Typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$.

Where:

IC = Total supply current

I_{CC} = Power-supply current with CMOS input levels

ΔICC = Power-supply current for a TTL high input (V_{IN} = 3.4 V)

D_H = Duty cycle for TTL inputs high N_T = Number of TTL inputs at D_H

ICCD = Dynamic current caused by an input transition pair (HLH or LHL)

f₀ = Clock frequency for registered devices, otherwise zero

f₁ = Input signal frequency

N₁ = Number of inputs changing at f₁

All currents are in milliamperes and all frequencies are in megahertz.

 \parallel Values for these conditions are examples of the I_{CC} formula.



Not more than one output should be shorted at a time. Duration of short should not exceed one second. The use of high-speed test apparatus and/or sample-and-hold techniques are preferable to minimize internal chip heating and more accurately reflect operational values. Otherwise, prolonged shorting of a high output can raise the chip temperature well above normal and cause invalid readings in other parametric tests. In any sequence of parameter tests, IOS tests should be performed last.

 $[\]$ Per TTL-driven input ($V_{IN} = 3.4 \text{ V}$); all other inputs at V_{CC} or GND

This parameter is derived for use in total power-supply calculations.

 $^{^{\#}}$ IC = ICC + Δ ICC \times DH \times NT + ICCD (f₀/2 + f₁ \times N₁)

CY74FCT823T 9-BIT BUS-INTERFACE REGISTER WITH 3-STATE OUTPUTS SCCS069A - OCTOBER 2001 - REVISED NOVEMBER 2001

timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figure 1)

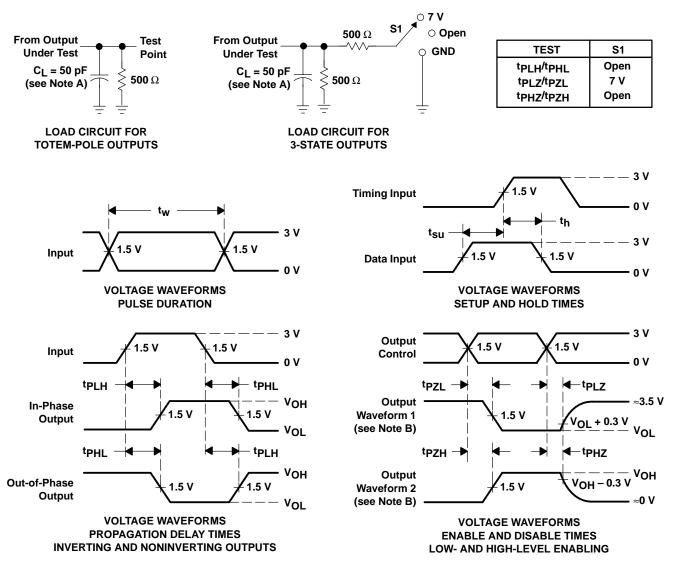
	DADAMETER	PARAMETER		CY74FC1	Г823AT	CY74FCT	823BT	CY74FCT	823CT	UNIT
	PARAMETER		TEST LOAD	MIN	MAX	MIN	MAX	MIN	MAX	UNIT
	Pulse duration	CP	C _L = 50 pF,	7		6		6		nc
t _w	Fuise duration	CLR low	$R_L = 500 \Omega$	6		6		6		ns
Ţ.	Catua tima hafara CD↑	Data	$C_L = 50 \text{ pF},$	4		3		3		no
t _{su}	Setup time, before CP↑	EN	$R_L = 500 \Omega$	4		3		3		ns
Ī.,	Hold time, after CP↑	Data	C _L = 50 pF,	2		1.5		1.5		20
th	Hold time, after CP1	EN	$R_L = 500 \Omega$	2		0		0		ns
t _{rec}	Recovery time	CLR before CP↑	$C_L = 50 \text{ pF},$ $R_L = 500 \Omega$	6		6		6		ns

switching characteristics over operating free-air temperature range (see Figure 1)

PARAMETER	FROM	то	TEST LOAD	CY74FC	Г823AT	CY74FCT823B	CY74FCT8	323CT	UNIT	
PARAMETER	(INPUT)	(OUTPUT)	TEST LOAD	MIN	MAX	MIN MA	(MIN	MAX	UNII	
^t PLH	СР	Y	C _L = 50 pF,		10	7.	5	6	ns	
^t PHL	OI .	•	$R_L = 500 \Omega$		10	7.	5	6	115	
^t PLH	СР	Y	$C_L = 300 \text{ pF},$		20	1	5	12.5	ns	
t _{PHL}	GF .		$R_L = 500 \Omega$		20	1	5	12.5	115	
^t PLH	CLR	Υ	$C_L = 50 \text{ pF},$ $R_L = 500 \Omega$		14		9	8	ns	
^t PZH	ŌE	Υ	$C_L = 50 \text{ pF},$		12		3	7	no	
t _{PZL}	OE	ī	$R_L = 500 \Omega$	$R_L = 500 \Omega$		12		3	7	ns
^t PZH	ŌE	Y	C _L = 300 pF,		23	1	5	12.5	ns	
tpzL	OL	ī	$R_L = 500 \Omega$		23	1	5	12.5	115	
^t PHZ	ŌE	Υ	C _L = 5 pF,		7	6.	5	6	ns	
tpLZ) <u> </u>	ſ	$R_L = 500 \Omega$		7	6.	5	6		
^t PHZ	ŌE	Y	C _L = 50 pF,		8	7.	5	6.5	ns	
tpLZ	5	ſ	$R_L = 500 \Omega$		8	7.	5	6.5	115	



PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms





PACKAGE OPTION ADDENDUM

6-Feb-2020

PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package	Pins	Package	Eco Plan	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Device Marking	Samples
	(1)		Drawing		Qty	(2)	(6)	(3)		(4/5)	
CY74FCT823ATQCT	ACTIVE	SSOP	DBQ	24	2500	Green (RoHS & no Sb/Br)	NIPDAU	Level-2-260C-1 YEAR	-40 to 85	FCT823A	Samples
CY74FCT823ATSOC	ACTIVE	SOIC	DW	24	25	Green (RoHS & no Sb/Br)	NIPDAU	Level-1-260C-UNLIM	-40 to 85	FCT823A	Samples
CY74FCT823CTSOC	ACTIVE	SOIC	DW	24	25	Green (RoHS & no Sb/Br)	NIPDAU	Level-1-260C-UNLIM	-40 to 85	FCT823C	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead/Ball Finish Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead/Ball Finish values may wrap to two lines if the finish value exceeds the maximum column width.

Important Information and Disclaimer: The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.



PACKAGE OPTION ADDENDUM

6-Feb-2020

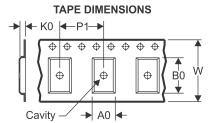
In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

PACKAGE MATERIALS INFORMATION

www.ti.com 26-Jan-2013

TAPE AND REEL INFORMATION





		Dimension designed to accommodate the component width
		Dimension designed to accommodate the component length
		Dimension designed to accommodate the component thickness
	W	Overall width of the carrier tape
ľ	P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	Package Type	Package Drawing			Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
CY74FCT823ATQCT	SSOP	DBQ	24	2500	330.0	16.4	6.5	9.0	2.1	8.0	16.0	Q1

www.ti.com 26-Jan-2013



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins SPQ		Length (mm)	Width (mm)	Height (mm)
CY74FCT823ATQCT	SSOP	DBQ	24	2500	367.0	367.0	38.0

DBQ (R-PDSO-G24)

PLASTIC SMALL-OUTLINE PACKAGE



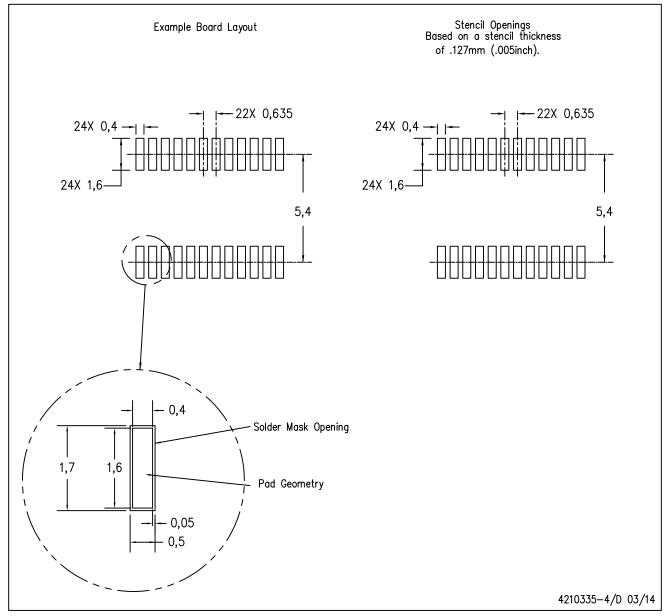
NOTES:

- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion not to exceed 0.006 (0,15) per side.
- D. Falls within JEDEC MO-137 variation AE.



DBQ (R-PDSO-G24)

PLASTIC SMALL OUTLINE PACKAGE



NOTES:

- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Example stencil design based on a 50% volumetric metal load solder paste. Refer to IPC-7525 for other stencil recommendations.



DW (R-PDSO-G24)

PLASTIC SMALL OUTLINE



NOTES: A. All linear dimensions are in inches (millimeters). Dimensioning and tolerancing per ASME Y14.5M-1994.

- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion not to exceed 0.006 (0,15).
- D. Falls within JEDEC MS-013 variation AD.



IMPORTANT NOTICE AND DISCLAIMER

TI PROVIDES TECHNICAL AND RELIABILITY DATA (INCLUDING DATASHEETS), DESIGN RESOURCES (INCLUDING REFERENCE DESIGNS), APPLICATION OR OTHER DESIGN ADVICE, WEB TOOLS, SAFETY INFORMATION, AND OTHER RESOURCES "AS IS" AND WITH ALL FAULTS, AND DISCLAIMS ALL WARRANTIES, EXPRESS AND IMPLIED, INCLUDING WITHOUT LIMITATION ANY IMPLIED WARRANTIES OF MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE OR NON-INFRINGEMENT OF THIRD PARTY INTELLECTUAL PROPERTY RIGHTS.

These resources are intended for skilled developers designing with TI products. You are solely responsible for (1) selecting the appropriate TI products for your application, (2) designing, validating and testing your application, and (3) ensuring your application meets applicable standards, and any other safety, security, or other requirements. These resources are subject to change without notice. TI grants you permission to use these resources only for development of an application that uses the TI products described in the resource. Other reproduction and display of these resources is prohibited. No license is granted to any other TI intellectual property right or to any third party intellectual property right. TI disclaims responsibility for, and you will fully indemnify TI and its representatives against, any claims, damages, costs, losses, and liabilities arising out of your use of these resources.

Tl's products are provided subject to Tl's Terms of Sale (www.ti.com/legal/termsofsale.html) or other applicable terms available either on ti.com or provided in conjunction with such Tl products. Tl's provision of these resources does not expand or otherwise alter Tl's applicable warranties or warranty disclaimers for Tl products.

Mailing Address: Texas Instruments, Post Office Box 655303, Dallas, Texas 75265 Copyright © 2020, Texas Instruments Incorporated